Mecwins was founded in 2008, and has developed a commercially viable optical characterization instrument based upon proprietary technology and patents.

Mecwins introduces a new instrument designed especially for the laboratory or research group that is interested in the static and dynamic characterization of single-chip cantilevers.

The SCALA µini was developed to characterize a single chip, in static or dynamic modes, and it can also be used to measure the thermal noise and frequencies associated with each cantilever. The platform is ideal for sensing, based upon its ability for profiling and dynamic analysis. An important aspect of the platform is that it can measure the deflection and vibration of practically any make or manufacture of cantilever, and is a simple yet powerful tool that can be used to get quick, reliable results for small to medium-sized research groups or laboratories.

Optical Characterization solutions for your research group and lab cantilever characterization requirements

Technical specifications of SCALA µini at a glance

- Deflection measurement range from 1 nm to 40 µm
- Scans practically any surface up to a 6mm x 6mm area
- X-Y resolution adapted to customer needs
- Liquid Cell (optional)
- Proprietary multi-functional software:
  - Profile detection measurements
  - Single point deflection measurements at any point on the mechanical sensor
- Frequency measurements (with thermal and mechanical excitation)